EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	291	(714/12).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/05 19:09
L2	672	(714/11).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/05 19:30
L3	218	714/31.ccls. and (compar\$3 verif\$4 confirm\$3)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2006/12/05 20:07
L4	179	(714/10).ccls. and (execut\$3 output result) same compar\$3	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2006/12/05 20:08
L5	12	(714/1,2,3,6,10,11,31).ccls. and ((service shadow\$3) near2 processor) near2 (discontinu\$3 deactivat\$3 disabl\$3 halt\$3 stop\$3 paus\$3)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2006/12/05 20:09
L6	47	(714/1,2,3,6,10,11,31).ccls. and ((service shadow\$3) near2 processor) with (discontinu\$3 deactivat\$3 disabl\$3 halt\$3 stop\$3 paus\$3)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2006/12/05 20:11
L7	6	(("5138708") or ("5148432") or ("5317726") or ("5488716") or ("5600784") or ("5845060")).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/05 20:18
L8	3	((second\$3 alternat\$3 backup) near2 (processor cpu microprocessor microcontroller) and (reliability reliable safe safety) and (compar\$3) and (second\$3 alternat\$3 backup) near2 (memory RAM) and (repeat\$4 continuously continually)).clm.	US-PGPUB	OR	ON	2006/12/05 20:22



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Select a search number (#)

- · Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- · Delete a search
- Run a search

Search Query Display

Tue, 5 Dec 2006, 8:31:03 PM EST

Recent Search Queries

#1

(((safer or safety or reliable or reliablity) and (program or code or routine or function) and (compare or comparing or compared) and (processor or microprocessor or microcontroller or cpu))

<in>metadata)



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